

Attachment A

No.	Serial No	TSMC No	Application Title	Filing Date	Assignment (Reel/Frame)
1	10/140,647	2001-0941	Prober Index Control for Remote Debugging by Web Browser	5/7/02	012902/0473
2	10/725,810	2001-0972	Method of the Adjustable Matching Map System in Lithography	12/2/03	014761/0759
3	10/694,428	2001-1094	Method of a Floating Pattern Loading System in Mask Dry-Etching Critical Dimension Control	10/27/03	015067/0473
4	10/672,403	2001-1457	Algorithms Tunning for Dynamic Lot Dispatching in Wafer and Chip Probing	9/26/03	014554/0202
5	10/286,626	2001-1265	Application of Impressed-Current Cathodic Protection to Prevent Metal Corrosion and Oxidation	11/2/02	013469/0539
6	10/134,820	2001-1349	Method for Measuring Gate-To-Body Current of Floating-Body PD SOI MOS Devices	4/28/02	012869/0369
7	10/822,197	2001-1440C	Embedded DRAM for Metal-Insulator-Metal (MIM) Capacitor Structure	4/9/04	Recorded 013982/0163 at the parent application USP6,720,232
8	10/749,698	2001-1510	Multivariate RBR Tool Aging Adjuster	12/31/03	014877/0720
9	10/081,985	2001-0725	Adjustment of N and K Values in a Darc Film	2/21/02	012644/0807
10	10/788,173	2001-1543	Chip Probing Equipment and Test Modeling for Next Generation MES(300MM)	2/26/04	015033/0283
11	10/631,842	2002-0228	Method to Form Self-Aligned Floating Gate to Diffusion Structures in Flash	7/31/03	Filed 7/31/03
12	10/406,122	2001-0938	High Performance Color Filter Process for Image Sensor	4/3/03	014181/0899
13	10/420,594	2001-0452B	Method to Fabricate Self-Aligned Source and Drain in Split Gate Flash	4/22/03	Recorded 012656/0769 at the parent application USP6,573,142
14	10/189,874	2001-0427	SCR-ESD Structures with Shallow Trench Isolation	7/5/02	013086/0425
15	10/726,105	2001-0427B	SCR-ESD Structures with Shallow Trench Isolation	12/2/03	Recorded 013086/0425 at the parent application USP6,720,622

16	10/810,965	2001-0413C	Novel Method to Improve Bump Reliability for Flip Chip Device	3/26/04	Recorded 012573/0276 at the parent application USP6,756,294
17	10/058,474	2001-0353	Electronic Customs Release Slip (E-CRS)	1/28/02	012553/0539
18	10/725,852	2001-0088B	Effective Vcc to Vss Power ESD Protection Device	12/2/03	Recorded 014859/0845 at the parent application USP6,682,993
19	10/357,138	2001-0043B	Novel Low Leakage Current Cascaded Diode Structure	2/3/03	Recorded 012326/0168 at the parent application USP6,537,868
20	10/628,778	2000-0659B	Novel Test Structure for Detecting Bridging of DRAM Capacitors	7/24/03	Recorded 011732/0773 at the parent application USP6,617,180
21	10/186,579	2000-0307B	Lossless Co-Planar Wave Guide in CMOS Process	7/1/02	Recorded 011498/0374 at the parent application USP6,465,367
22	10/272,086	2002-0227	Method to Form Self-Aligned Split Gate Flash with L-Shaped Wordline Spacers	10/18/02	013408/0312

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